Abstracts

Thermal transients in microwave active devices and their influence on intermodulation distortion

S. David, W. Batty, A.J. Panks, R.G. Johnson and C.M. Snowden. "Thermal transients in microwave active devices and their influence on intermodulation distortion." 2001 MTT-S International Microwave Symposium Digest 01.1 (2001 Vol. I [MWSYM]): 431-434 vol.1.

A fully physical transient thermal model is used to investigate the effects of temperature on the intermodulation distortion performance of microwave devices. A 24 mm, 60 finger PHEMT is used to compare measurements with predictions from the model. Results are in very good agreement and are a strong indication of thermally induced intermodulation distortion.

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